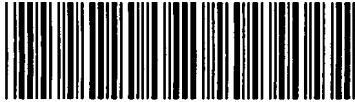


Search Notes



Application/Control No.

10/523,512

Examiner

Tien Dinh

Applicant(s)/Patent under
Reexamination

LIEBE ET AL.

Art Unit

3644

SEARCHED

Class	Subclass	Date	Examiner
244	149.3		
	201		
	204.1	11/26	DB
229	214.2		
	214.23	11/06	DB
405	80	8/07	DB
137	561A	8/07	DB
138	40		
	43	5/07	DB

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Same as above		7/07	DB

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East Text	11/06	DB